

## IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of:

Date: September 7, 2001

B.S. Beaman et al.

Group Art Unit: 2858

Serial No.: 09/251,988

Examiner: Jermele M. Hollington

Filed: February 17, 1999

Docket No.: YO999-088

For: Structural Design And Processes To Control Probe Position Accuracy  
In A Wafer Test Probe AssemblyAssistant Commissioner for Patents  
Washington, D.C. 20231

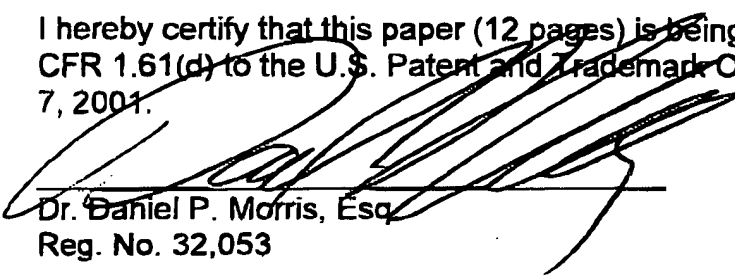
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## CERTIFICATE OF FACSIMILE TRANSMISSION

I hereby certify that this paper (12 pages) is being facsimile transmitted under Rule 37 CFR 1.61(d) to the U.S. Patent and Trademark Office to (703) 308-7722 on September 7, 2001.

  
Dr. Daniel P. Morris, Esq.  
Reg. No. 32,053SUBSTITUTE AMENDMENT IN RESPONSE TO NOTICE OF NON-COMPLIANT  
AMENDMENT (37 CFR 1.121) DATED 7-26-01

Sir:

In response to Office Action dated January 19, 2001, please consider the following:

## IN THE SPECIFICATION

Amend the paragraph bridging pages 7 and 8 as follows:

"Turning now to the figures, Figures 2 and 3 show two embodiments of the test assembly according to the present invention. Numerals common between Figures 2 and 3 represent the same thing. Probe head 40 is formed from a plurality of elongated electrically conducting members 42 embedded in a material 44 which is preferably